



Ion beam analysis: a family of versatile techniques for materials characterization

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Ion beam analysis in materials science

a family...



case dependent
combination (total IBA)

...of complementary techniques

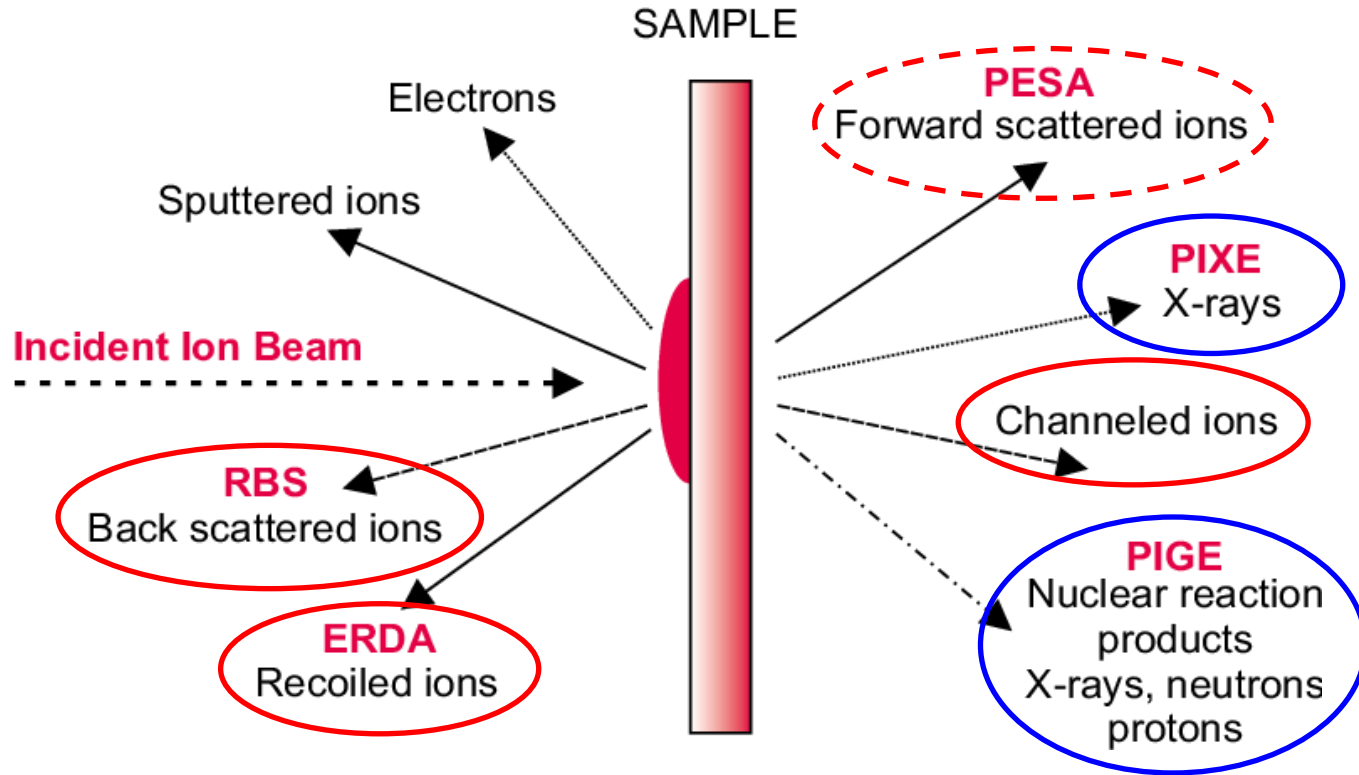
compositional depth profile

+ crystalline structure (channeling)

wide range of materials/samples

from thick coatings (up to 1 μm) to nanoparticles

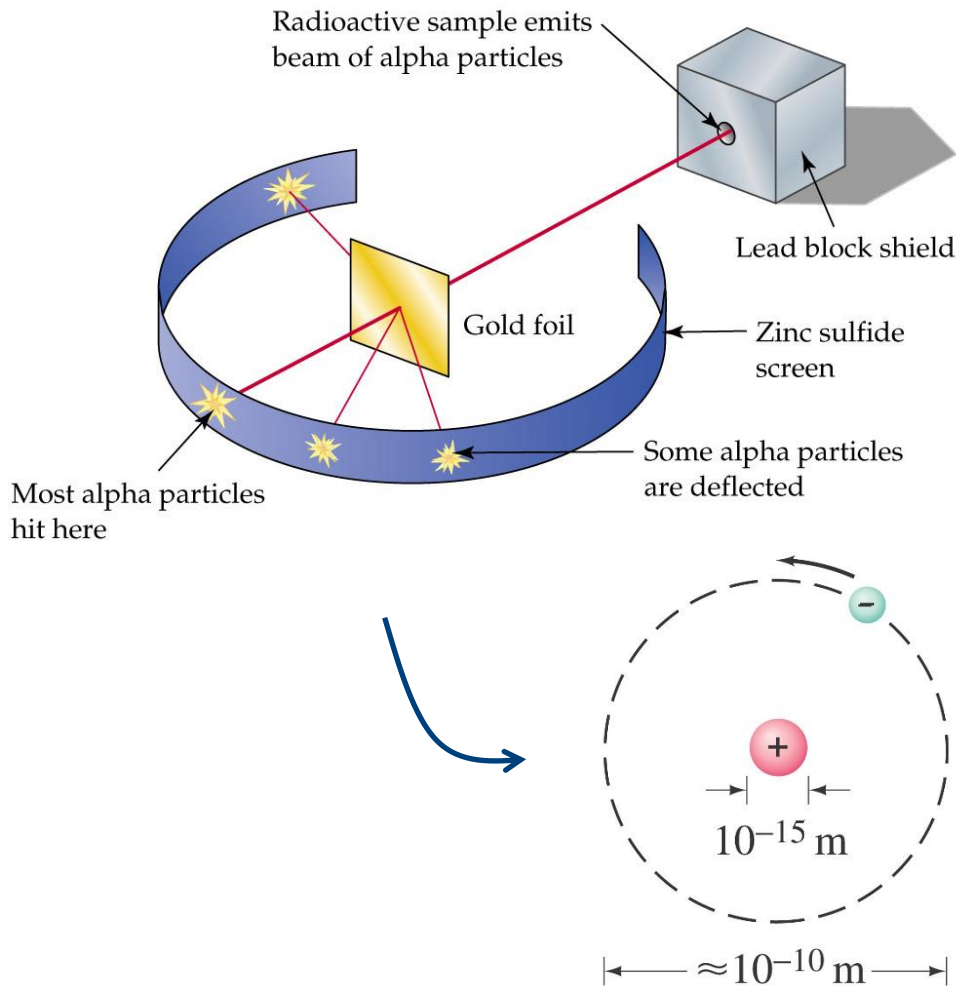
Ion beam analysis



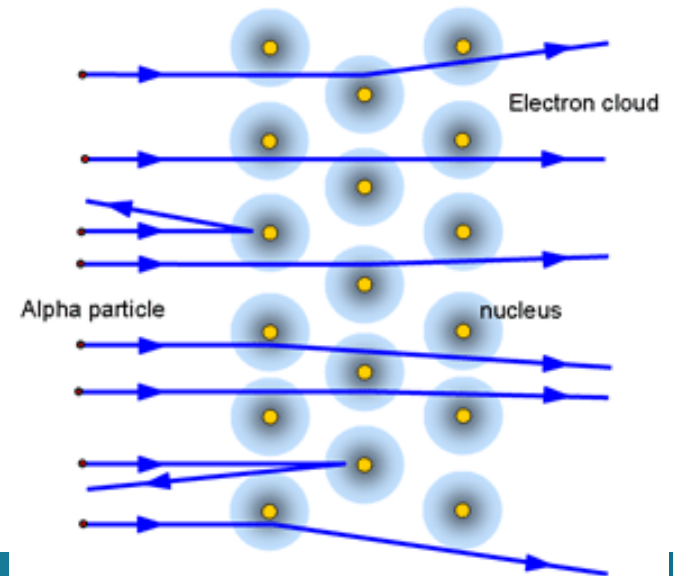
key: interaction between ion and solid

Pioneering experiment

interaction of **ions** with **atoms**



Ernest Rutherford (H. Geiger – E. Marsden)



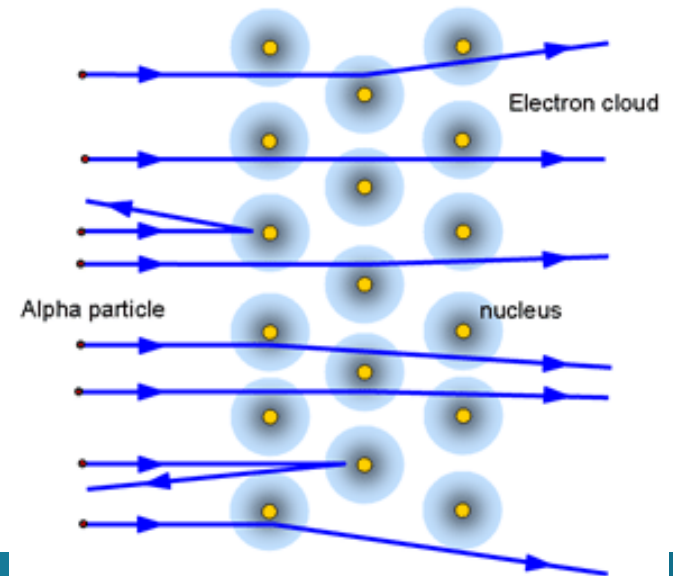
Pioneering experiment

interaction of **ions** with **nuclei** and with **electrons**

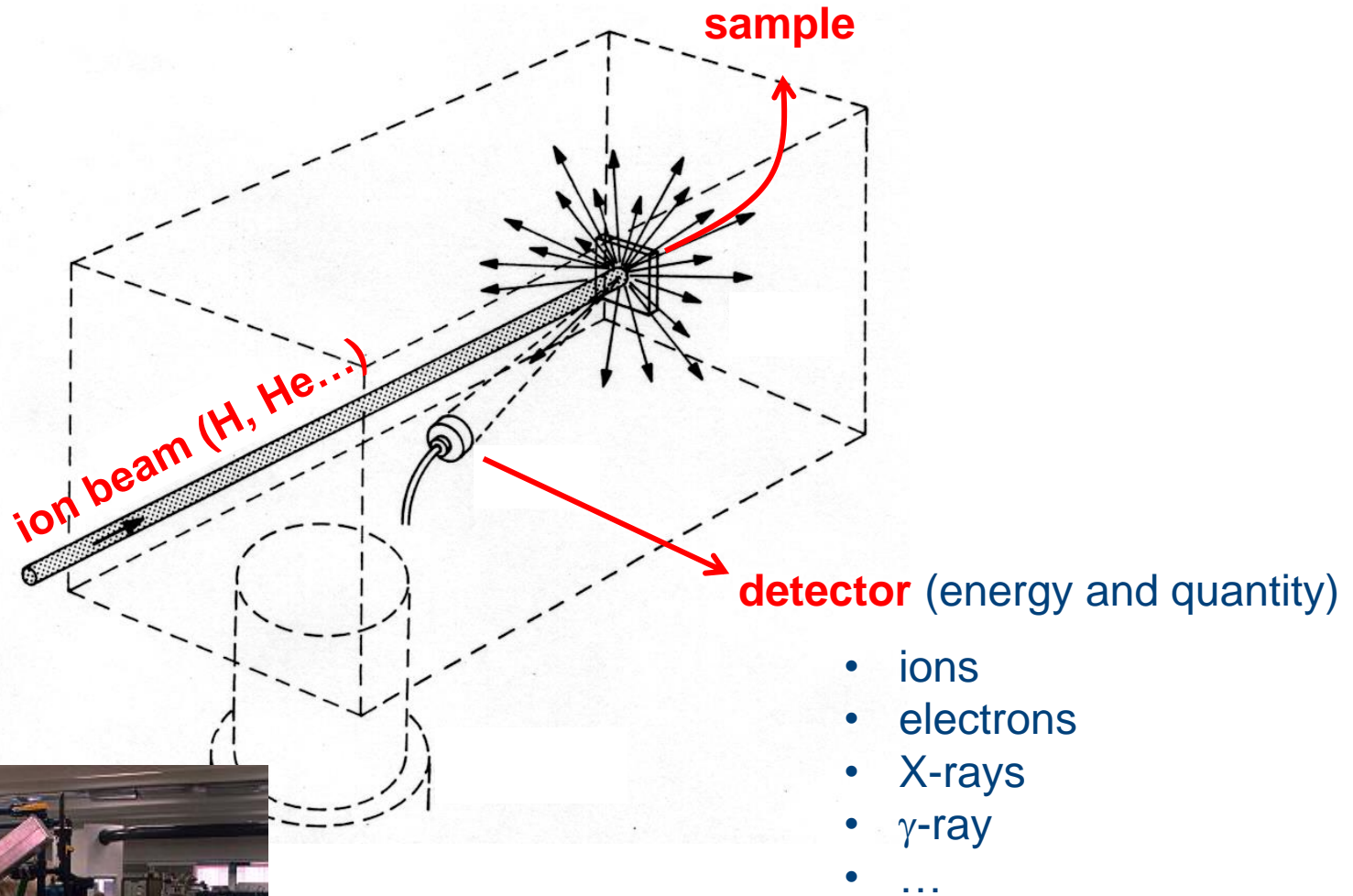
interaction via **scattering/recoil** or **energy loss/excitation**

- conservation of momentum
- conservation of energy
- conservation of angular momentum
- Rutherford model
- Bohr model
- ...

quantitative
(standardless)



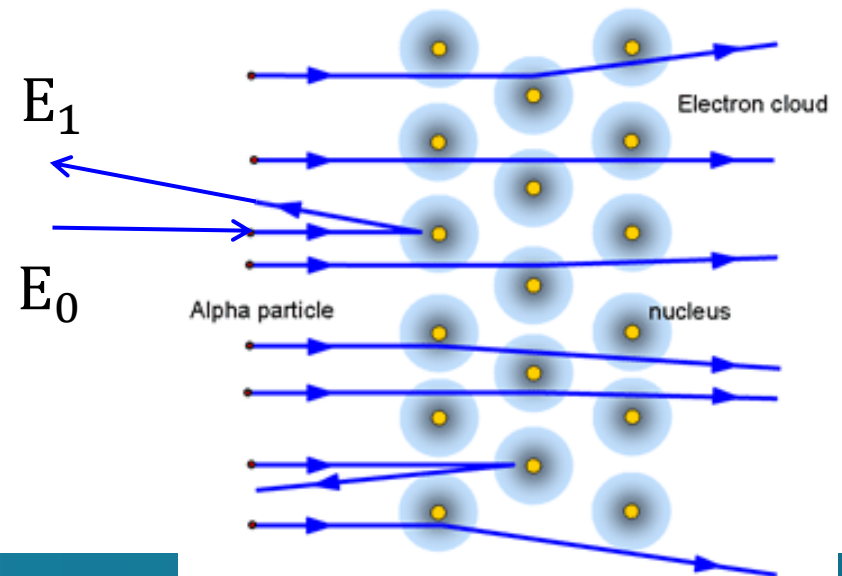
Concept of ion beam analysis



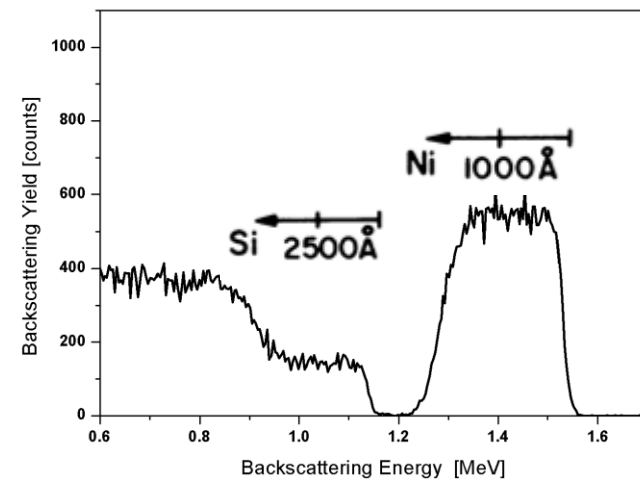
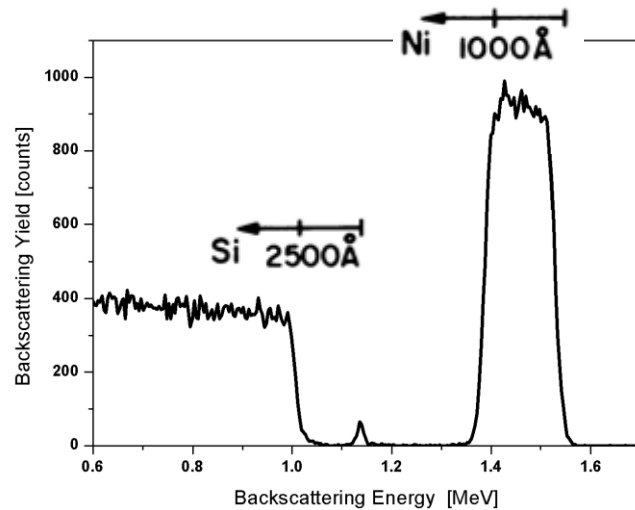
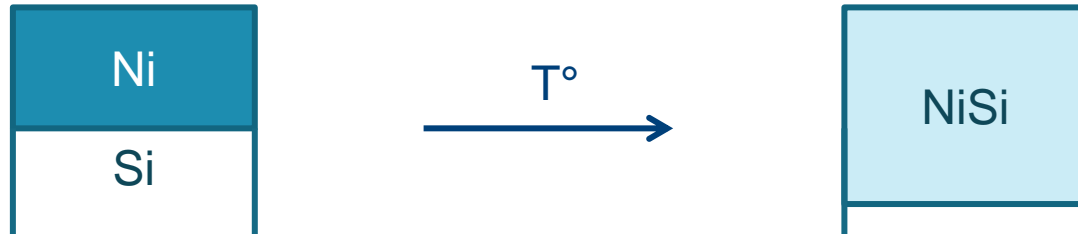
Rutherford backscattering spectrometry

1. energy transfer during the collision of M_1 and M_2
(kinematic factor) → **identity (M_2)** of the target atoms
2. cross section in central force field
(scattering cross section) → **concentration** of target atoms
3. energy loss of particle
(stopping cross section) → **depth profiles**

compositional depth profile



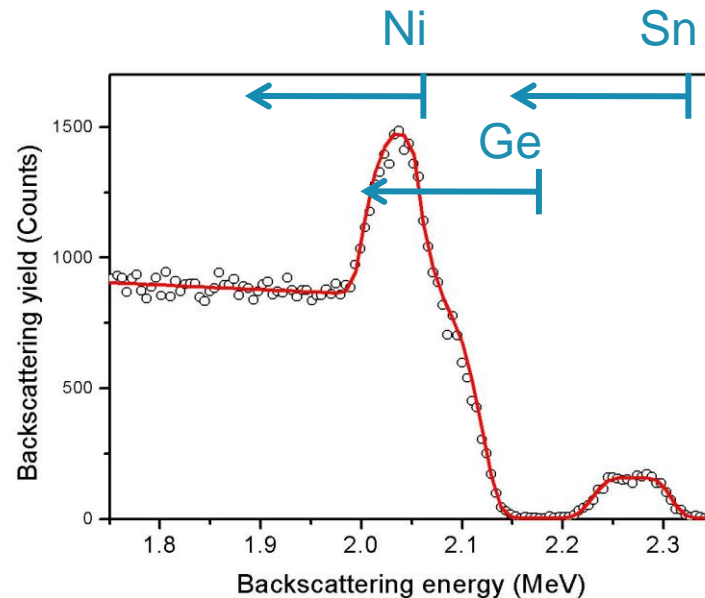
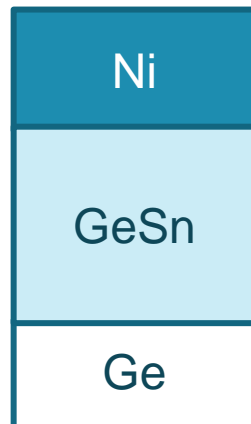
Rutherford backscattering spectrometry



- correct phase identification
- correct thickness analysis
- no matrix nor chemical effects

- no chemical information
- potential overlap of signals...

Rutherford backscattering spectrometry



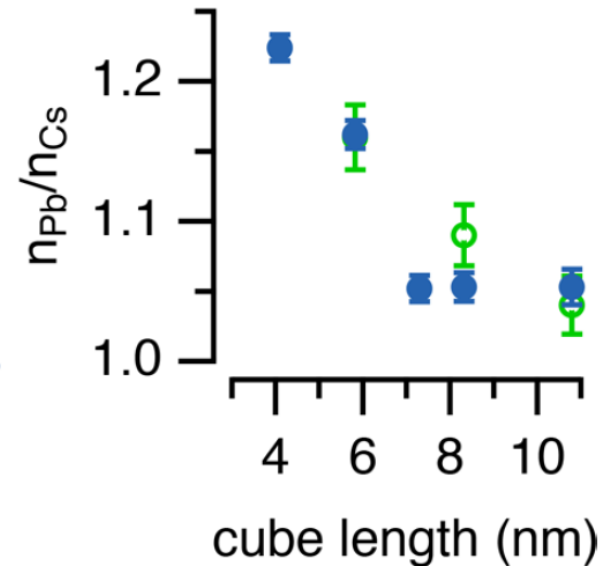
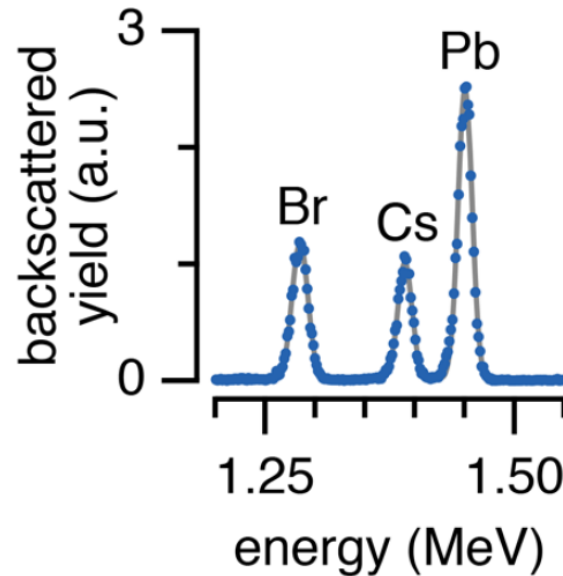
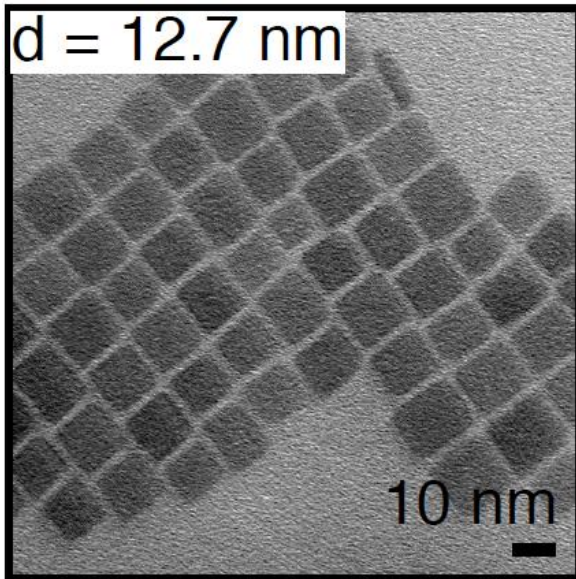
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Composition of a nanoparticle

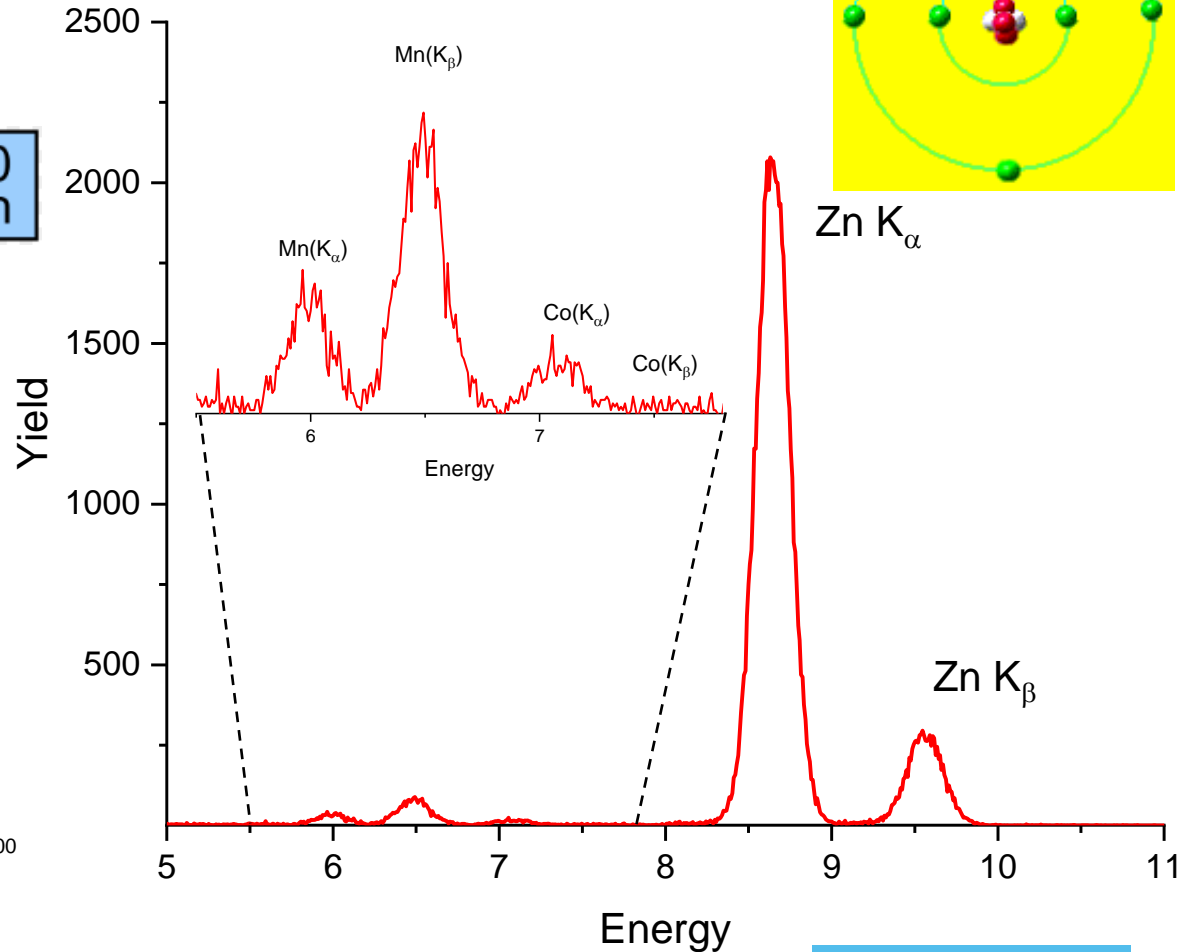
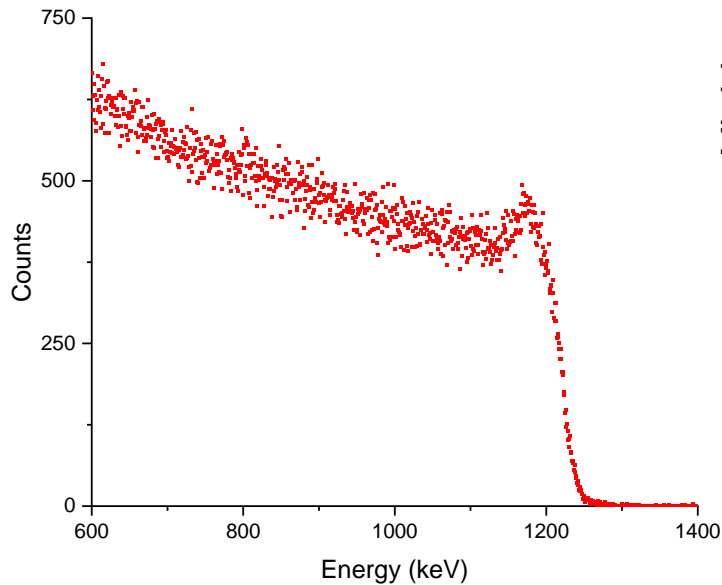
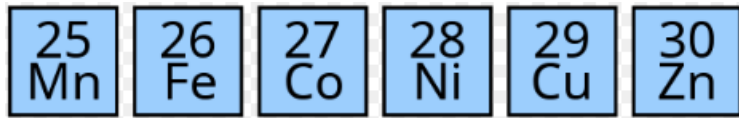
too small for a nanobeam: by far more recoil than scatter events

- exact composition? stoichiometric?
- terminated by excess metal cations?



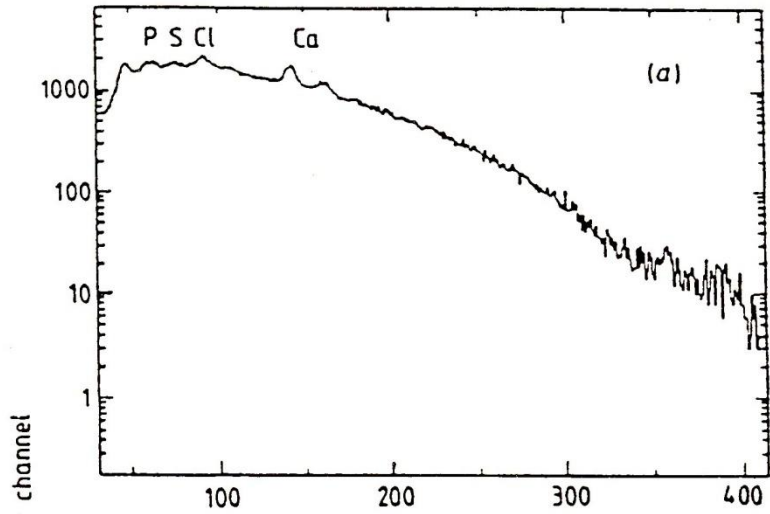
PIXE: particle induced X-ray emission

ZnO doped
with Co and Mn



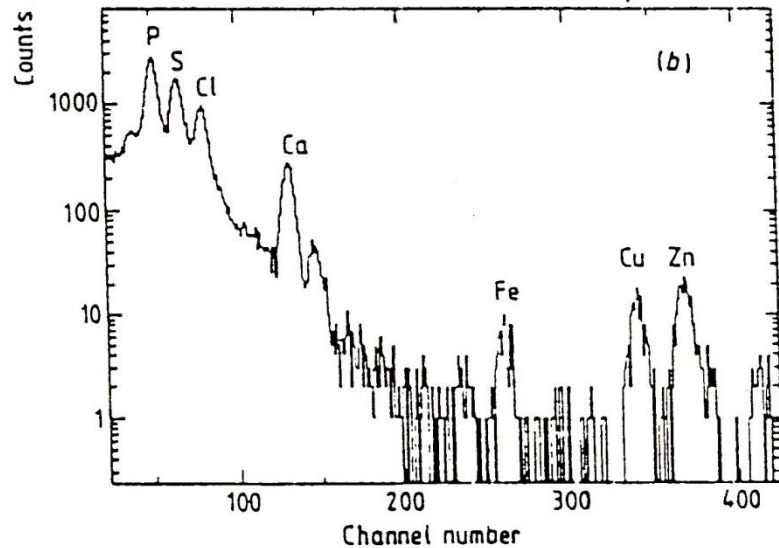
PIXE vs. EMA

EMA
(electron)



easier beam focus

PIXE
(proton)



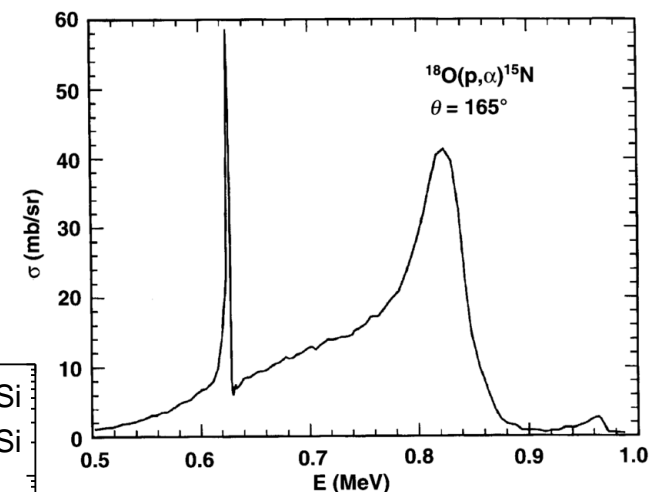
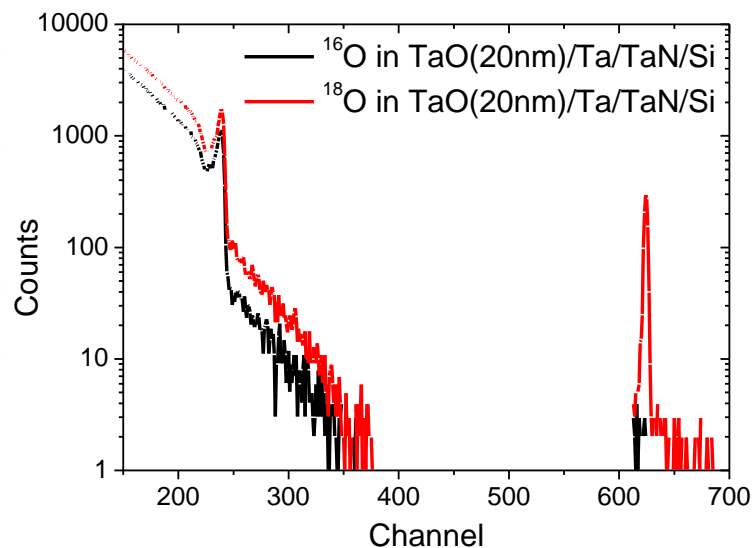
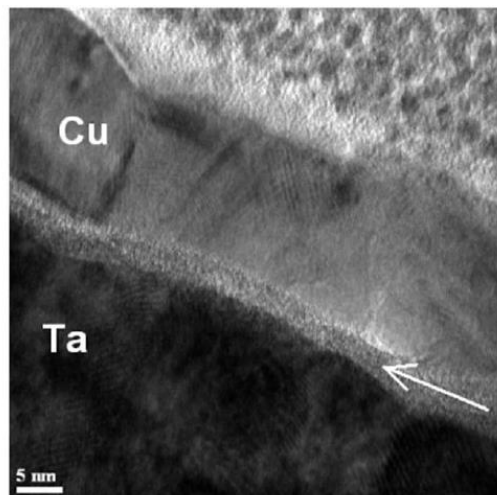
less Bremsstrahlung

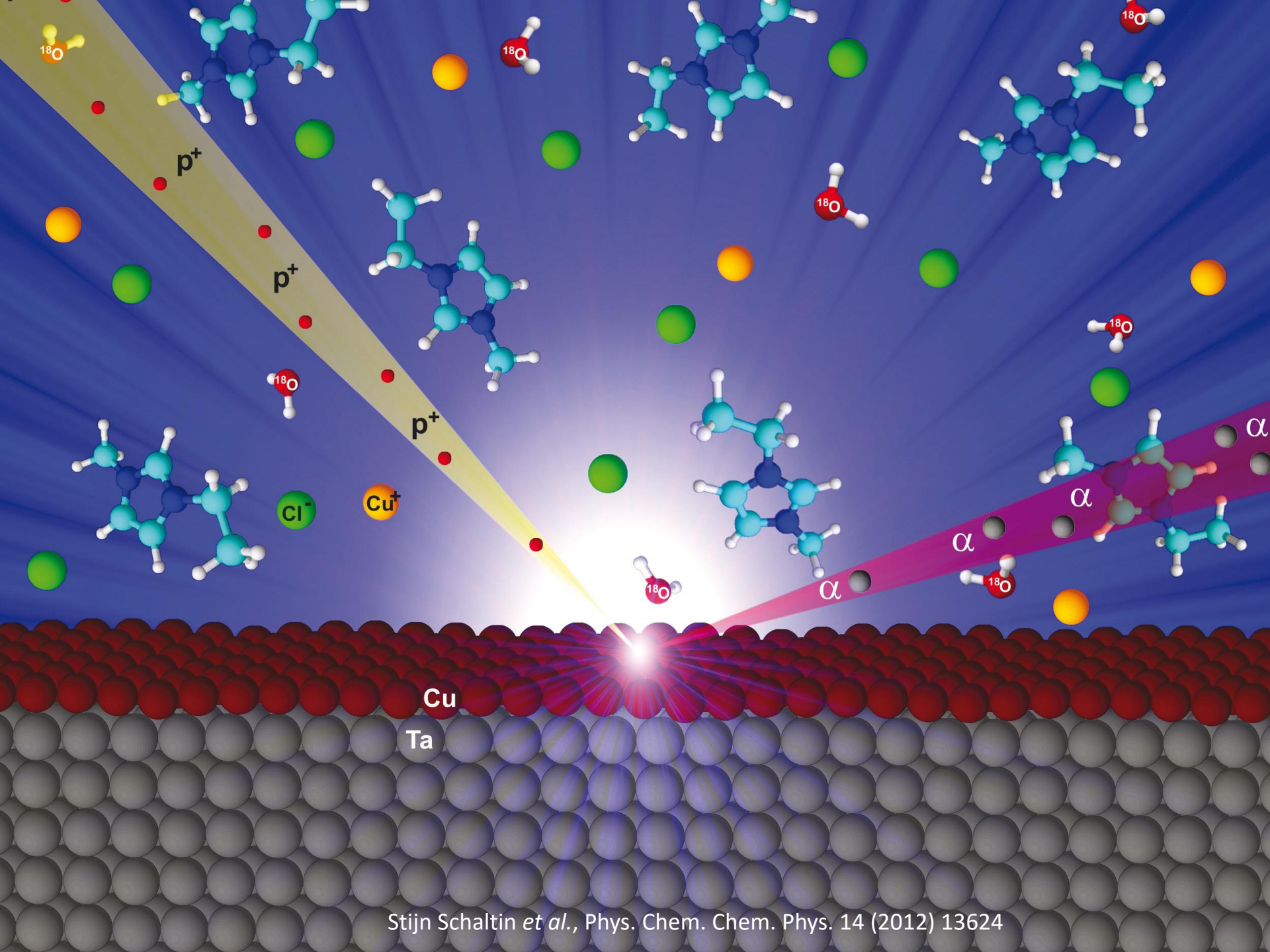
NRA: nuclear reaction analysis

Ta oxidation in high vacuum: $^{18}\text{O}(p,\alpha)^{15}\text{N}$ resonance (629 keV)

↪ natural abundance: 0.21 %

Direct electroplating of copper on tantalum from ionic liquids



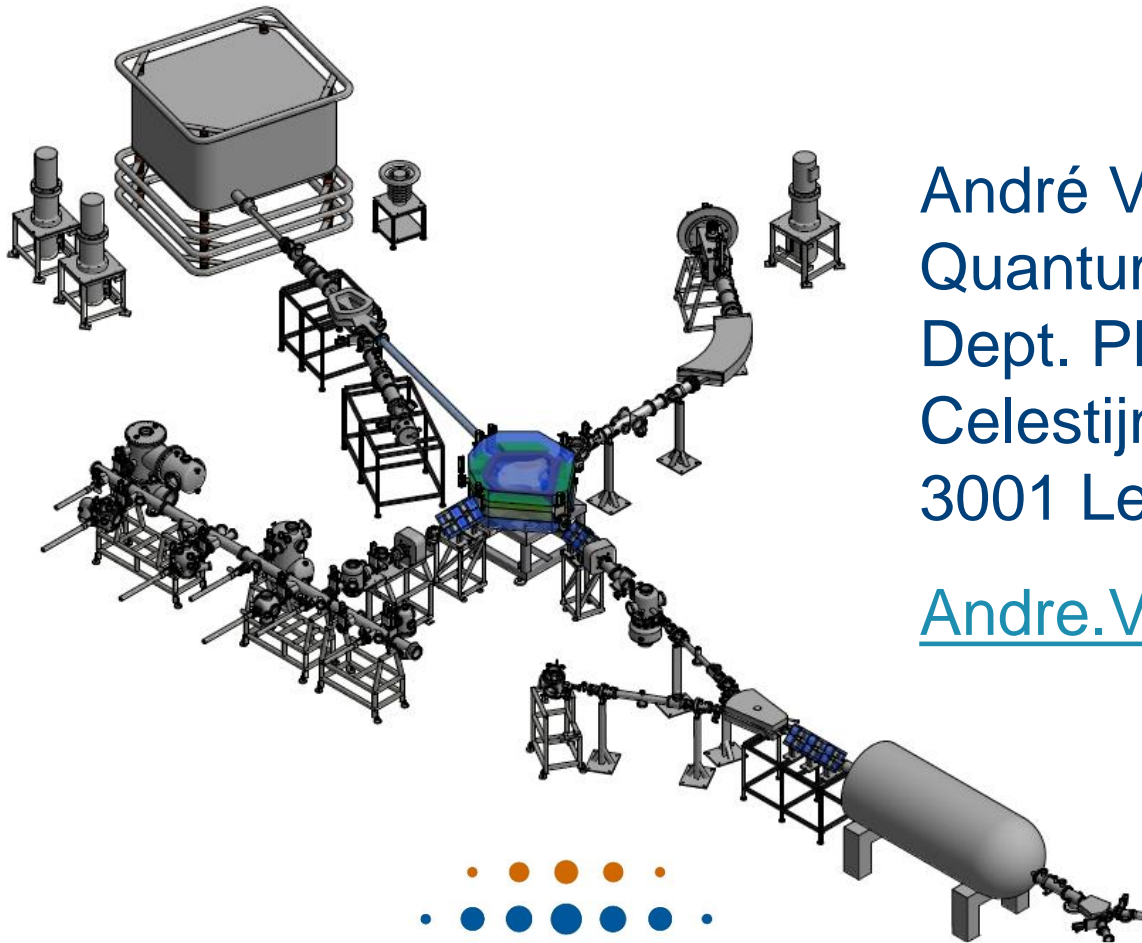


IBA: strengths and limitations

- + • very versatile – determining compositional depth profile
- from the surface to (a few) μm deep
- quantitative – based on fundamental conservation laws
- independent of matrix, chemistry...
- *in situ* (during heating, laser irradiation...)

- • mm-sized ion beam (but: use ensembles)
- mass resolution (but: PIXE, NRA...)
- individual techniques may lack sensitivity in specific cases (but: use complementary techniques – TOTAL IBA)

Ion and Molecular Beam Laboratory



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Research And Development with Ion
Beams – Advancing Technology in Europa

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